



LIGITEK ELECTRONICS CO.,LTD.

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SUPER BRIGHT ROUND TYPE LED LAMPS

Ozdisan



Lead-Free Parts

LURF3333S/S255-LTS-PF-OD

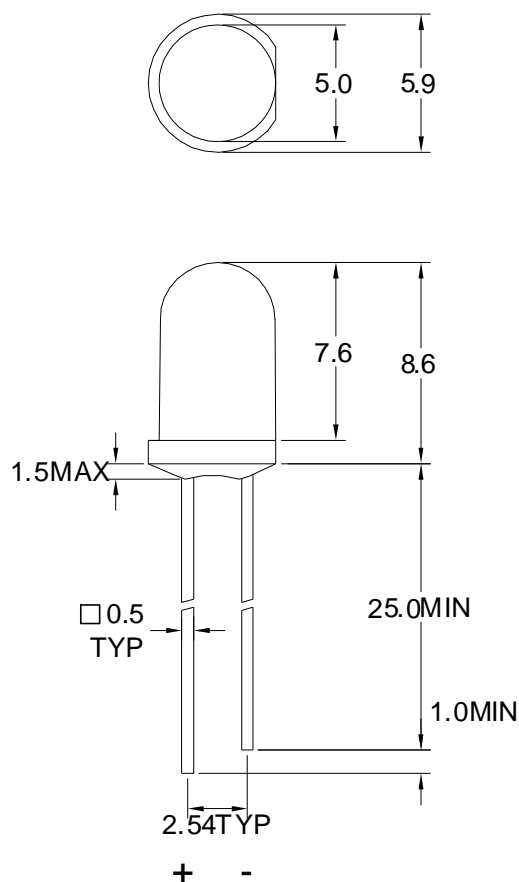
## DATA SHEET

DOC. NO : QW0905-LURF3333S/S255-LTS-PF-OD

REV. : A

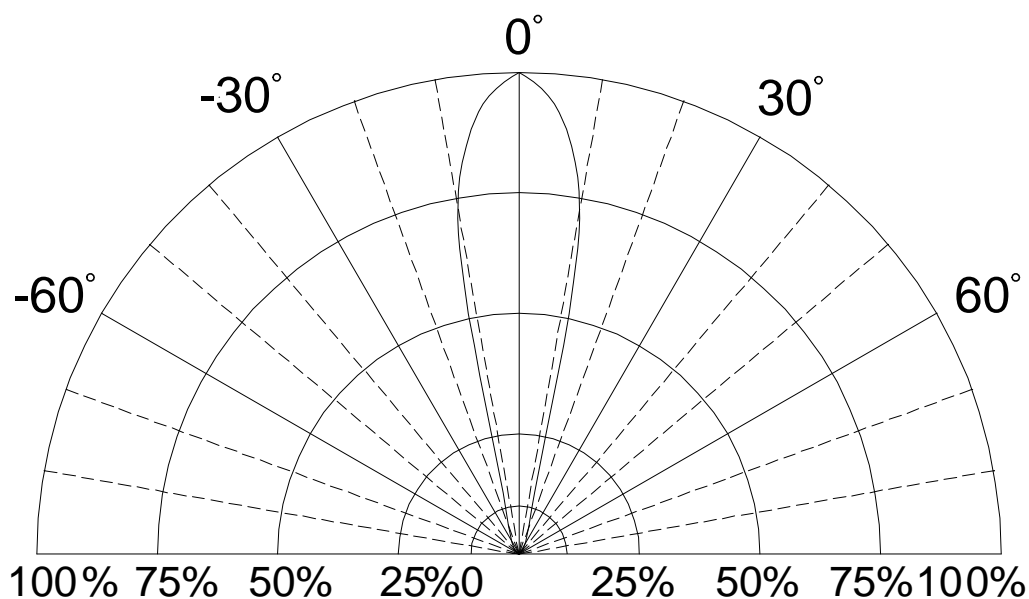
DATE : 7-Nov.-2022

## Package Dimensions



Note : 1. All dimension are in millimeter tolerance is  $\pm 0.25\text{mm}$  unless otherwise noted.  
 2. Specifications are subject to change without notice.

## Directivity Radiation



## Absolute Maximum Ratings at Ta=25 °C

Parameter	Symbol	Ratings	UNIT
		URF(S)	
Forward Current	IF	50	mA
Peak Forward Current Duty 1/10@10KHz	IFP	90	mA
Power Dissipation	PD	120	mW
Reverse Current @5V	Ir	10	μA
Electrostatic Discharge( * )	ESD	2000	V
Operating Temperature	Topr	-40 ~ +85	°C
Storage Temperature	Tstg	-40 ~ +100	°C

\* Static Electricity or power surge will damage the LED. Use of a conductive wrist band or anti-electrostatic glove is recommended when handling these LED. All devices, equipment and machinery must be properly grounded.

## Typical Electrical & Optical Characteristics (Ta=25 °C)

PART NO	MATERIAL	COLOR		Dominant wave length λ Dnm	Spectral halfwidth Δ λ nm	Forward voltage @ 20mA(V)		Luminous intensity @ 20mA(mcd)		Viewing angle 2θ 1/2 (deg)
		Emitted	Lens			Min.	Max.	Min.	Typ.	
LURF3333S/S255-LTS-PF-OD	AlGaInP	Red	Water Clear	625	20	1.7	2.6	11500	17000	22

Note: 1.The forward voltage data did not including ±0.1V testing tolerance.  
2.The luminous intensity data did not including ±15% testing tolerance.  
3.The products should be stored at 15°C ~ 25°C and 25% ~ 65%RH after being shipped from the factory and the storage life limits are 12 months.

## Brightness Code For Standard LED Lamps

URF(S) CHIP

Group	Luminous Intensity(mcd) at 20 mA	
	Min.	Max.
A33	11500	14000
A34	14000	17000
A35	17000	21000
A36	21000	26000
A37	26000	32000

Group	Wave length(nm) at 20 mA	
	Min.	Max.
27	620	625
28	625	630

Group	Forwardvoltage(V) at 20mA	
	Min.	Max.
V1	1.6	1.8
V2	1.8	2.0
V3	2.0	2.2
V4	2.2	2.4

## Typical Electro-Optical Characteristics Curve

### URFS CHIP

Fig.1 Forward current vs. Forward Voltage

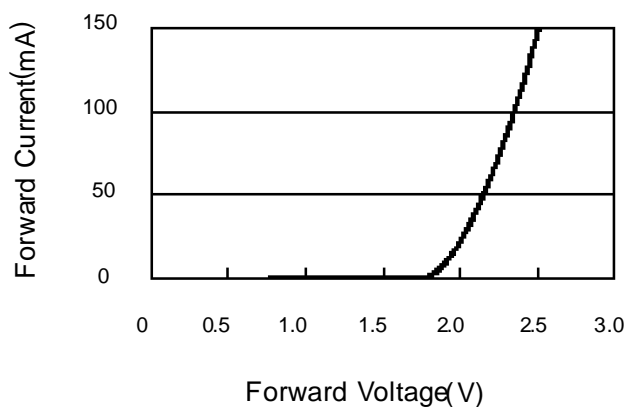


Fig.2 Luminous Intensity vs. Forward Current

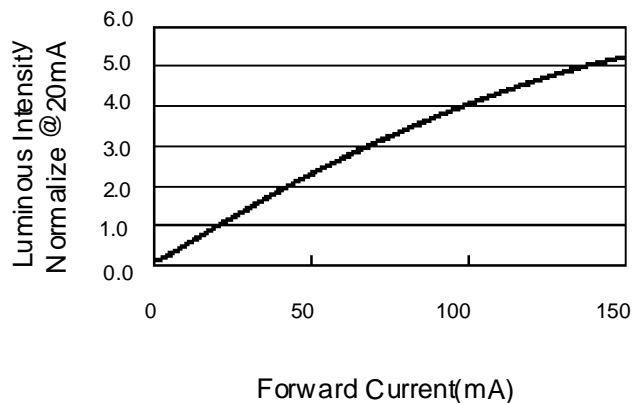


Fig.3 Forward Voltage vs. Temperature

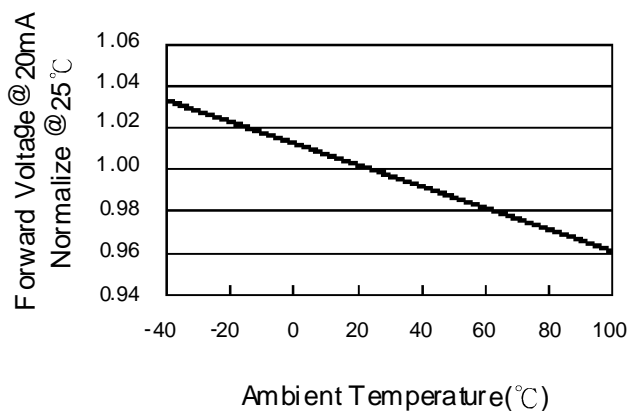


Fig.4 Luminous Intensity vs. Temperature

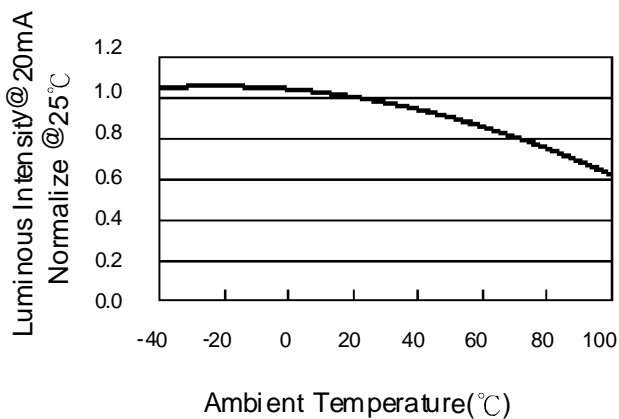
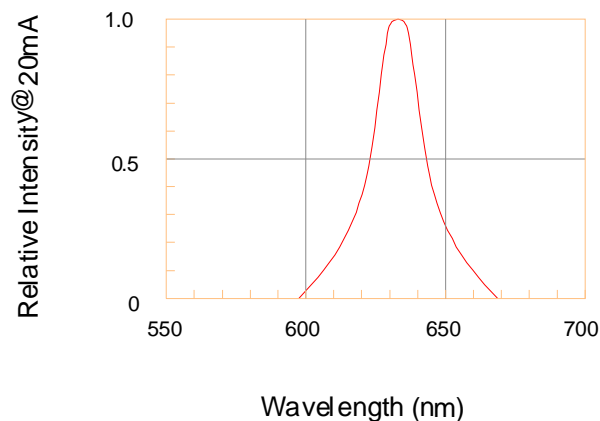


Fig.5 Relative Intensity vs. Wavelength



**Soldering Condition(Pb-Free)****1.Iron:**

Soldering Iron:30W Max

Temperature 350° C Max

Soldering Time: 3 Seconds Max(One time only)

Distance:2mm Min(From solder joint to body)

**2.Wave Soldering Profile**

Dip Soldering

Preheat: 1 20° C Max

Preheat time: 60seconds Max

Ramp-up

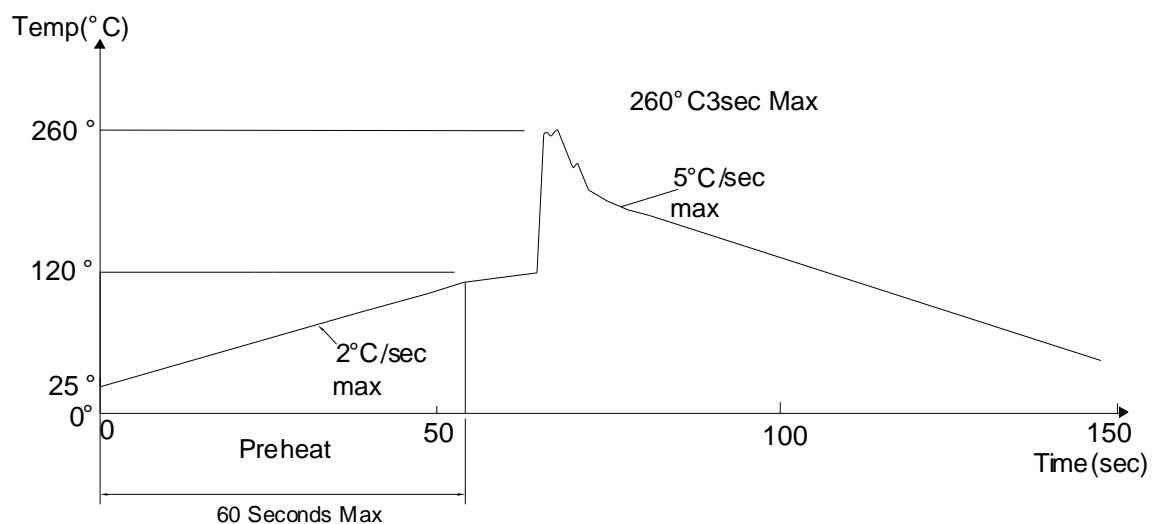
2° C/sec(max)

Ramp-Down:-5° C/sec(max)

Solder Bath:260° C Max

Dipping Time:3 seconds Max

Distance:2mm Min(From solder joint to body)



Note: 1. Wave solder should not be made more than one time.

2. You can just only select one of the soldering conditions as above.

## Reliability Test

Test Item	Test condition	Description	Reference Standard
Operating Life Test	1.Under Room Temperature 2.If=20mA 3.t=1000 hrs (-24hrs, +72hrs)	This test is conducted for the purpose of determining the resistance of a part in eletrical and thermal stressed.	MIL-STD-750:1026 MIL-STD-883:1005 JIS C 7021:B-1
High Temperature Storage Test	1.Ta=105°C±5°C 2t=1000 hrs (-24hrs, +72hrs)	The purpose of this test is the resistance of the device which is laid under condition of high temperature for hours.	MIL-STD-883:1008 JIS C 7021:B-10
Low Temperature Storage Test	1.Ta=-40°C±5°C 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this test is the resistance of the device which is laid under condition of low temperature for hours.	JIS C 7021:B-12
High Temperature High Humidity Test	1.Ta=65°C±5°C 2.RH=90%~95% 3.t=240hrs±2hrs	The purpose of this test is the resistance of the device under tropical for hours	MIL-STD-202:103B JIS C 7021: B-11
Thermal Shock Test	1.Ta=105°C±5°C&-40°C±5°C (10min) (10min) 2.Total 10 cycles	The purpose of this test is resistance of the device to sudden extreme changes in high and low temperature.	MIL-STD-202:107D MIL-STD-750:1051 MIL-STD-883:1011
Solder Resistance Test	1.T.Sol=260°C±5°C 2.Dwell time=10±1sec.	This test intened to determine the thermal characteristic trssitance of the device to sudden exposures at extreme changes in temperature when soldering the lead wire.	MIL-STD-202:210A MIL-STD-750:2031 JIS C 7021:A-1
Solderability Test	1.T.Sol=245°C±5°C 2.Dwell time=5±1sec.	This test intened to see soldering well performed or not	MIL-STD-202:208D MIL-STD-750:2026 MIL-STD-883:2003 JIS C 7021:A-2